

CLAIMS

1 1. A method of recovering from ground bounce during a boundary
2 scan test, said method comprising the step of operationally transitioning a
3 Test Access Port controller from any of at least three undetermined controller
4 states induced by the ground bounce to a determined controller state.

1 2 The method recited in claim 1 wherein the at least three
2 undetermined controller states are selected from the group consisting of an
3 UPDATE state, a RUN-TEST/IDLE state, a SELECT-DR-SCAN state, and a
4 CAPTURE-DR state.

1 3. The method recited in claim 2 wherein the at least three
2 undetermined controller states are selected from the group consisting of an
3 UPDATE state, a RUN-TEST/IDLE state, and a SELECT-DR-SCAN state.

1 4. The method recited in claim 1 wherein the determined controller
2 state is UPDATE-DR.

1 5. The method recited in claim 1 wherein the at least three
2 undetermined controller states includes four undetermined states selected

3 from the group consisting of an UPDATE state, a RUN-TEST/IDLE state, a
4 SELECT-DR-SCAN state, and a CAPTURE-DR state.

1 6. The method recited in claim 1, wherein the controller
2 transitioning step further comprises the step of providing a low Test Mode
3 Select input to the TAP controller prior to a falling edge of a clock signal while
4 in an UPDATE state.

1 7. The method recited in claim 6 wherein the controller
2 transitioning step further comprises the step of providing the Test Access Port
3 controller with a Test Mode Select input having the following bit pattern for a
4 consecutive series of rising edges of clock pulses: a plurality of lows, high, a
5 plurality of lows, high, high.

1 8. The method recited in claim 6 wherein the controller
2 transitioning step further comprises the step of providing the Test Access Port
3 with a Test Mode Select input having the following bit pattern for a
4 consecutive series of clock rising edges of pulses: low, high, low, high, high.

1 9. A boundary scan apparatus with ground bounce recoverability
2 comprising:
3 at least one Test Access Port controller; and

4 means for operationally transitioning the Test Access Port
5 controller from any of at least three undetermined controller states induced by
6 the ground bounce to a determined controller state.

1 10. The apparatus recited in claim 9 wherein the controller state
2 transitioning means comprises means for providing the Test Access Port
3 controller with a low Test Mode Select input prior to a falling edge of a clock
4 signal while in an update state.

1 11. The apparatus recited in claim 10 wherein the determined
2 controller state is UPDATE-DR.

1 12. The apparatus recited in claim 11 wherein the at least three
2 undetermined controller states are selected from the group consisting of an
3 UPDATE state, a RUN-TEST/IDLE state, a SELECT-DR-SCAN state, and
4 CAPTURE-DR state.

1 13. The apparatus recited in claim 12 wherein the at least three
2 undetermined controller states are selected from the group consisting of an
3 UPDATE state, a RUN-TEST/IDLE state, and SELECT-DR-SCAN state.

1 14. The apparatus recited in claim 12 wherein the at least three
2 undetermined controller states are four undetermined controller states
3 selected from the group consisting of an UPDATE state, a RUN-TEST/IDLE
4 state, a SELECT-DR-SCAN state, and a CAPTURE-DR state.

1 15. The apparatus recited in claim 14 wherein the controller state
2 transitioning means comprises means for providing the Test Access Port
3 controller with a Test Mode Select input having the following bit pattern for a
4 consecutive series of rising edges of clock pulses: a plurality of lows, high, a
5 plurality of lows, high, high.

1 16. The apparatus recited in claim 13 wherein the controller state
2 transitioning means comprises means for providing the Test Access Port with
3 a Test Mode Select input having the following bit pattern for consecutive
4 series of rising edges clock pulses: low, high, low, high, high.

1 17. A boundary scan apparatus with ground bounce recoverability,
2 comprising:
3 an in-circuit tester configured to provide a Test Access Port
4 controller with a low Test Mode Select input prior to a transition from an
5 update state; and

6 said in-circuit tester further configured to operationally transition
7 the Test Access Port controller from any of at least four undetermined
8 controller states induced by the ground bounce to an UPDATE-DR state.

1 18. The apparatus recited in claim 17 wherein the at least four
2 undetermined controller states are selected from the group consisting of an
3 UPDATE state, RUN-TEST/IDLE, SELECT-DR-SCAN, and CAPTURE-DR.

1 19. The apparatus recited in claim 17 wherein the in-circuit tester is
2 further configured to provided the Test Access Port controller with a Test
3 Mode Select input having the following bit pattern for a consecutive series of
4 rising edges of clock pulses: a plurality of lows, high, a plurality of lows, high,
5 high.

1 20. The apparatus recited in claim 18 wherein the in-circuit tester is
2 further configured to provided the Test Access Port controller with a Test
3 Mode Select input having the following bit pattern for a consecutive series of
4 rising edges of clock pulses: a plurality of lows, high, a plurality of lows, high,
5 high.

1 21. The apparatus recited in claim 17 wherein the in-circuit tester is
2 further configured to operationally transition the Test Access Port controller
3 from an undetermined data state to a determined data state.

1 22. The apparatus recited in claim 21 wherein said data state
2 transition begins when the Test Access Port controller has reached the
3 UPDATE-DR state.

1 23. The apparatus recited in claim 17 wherein the Test Access Port
2 controller is one of a plurality of controllers in a boundary scan chain.

1 24. The apparatus recited in claim 20 wherein the Test Access Port
2 controller is one of a plurality of controllers in a boundary scan chain.

1 25. The apparatus recited in claim 21 wherein the Test Access Port
2 controller is one of a plurality of controllers in a boundary scan chain.

1 26. The apparatus recited in claim 22 wherein the Test Access Port
2 controller is one of a plurality of controllers in a boundary scan chain.